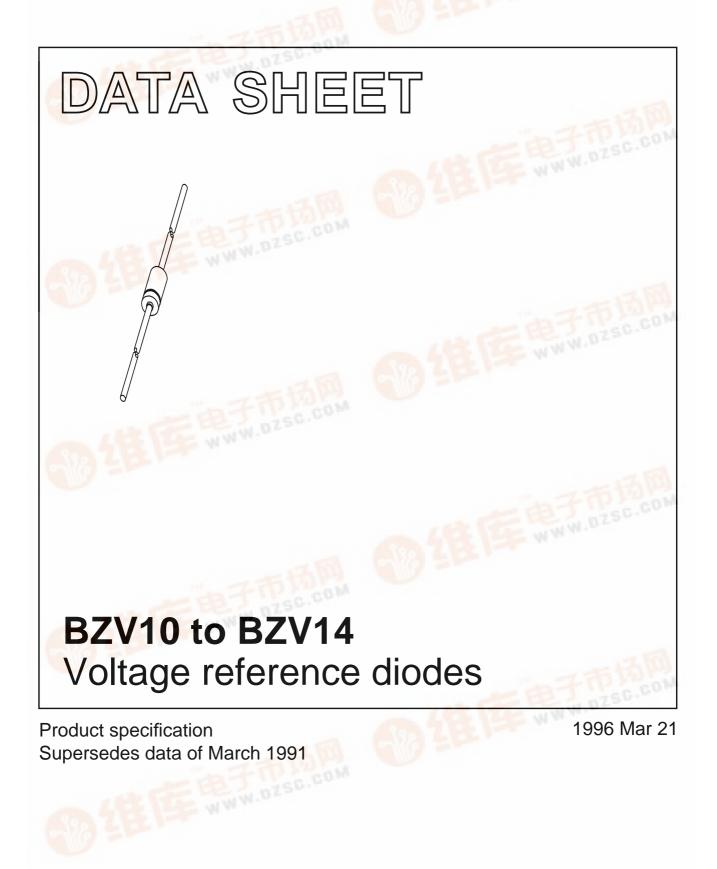
DISCRETE SEMICONDUCTORS









BZV10 to BZV14

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MAM216

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FEATURES

- Temperature compensated
- Reference voltage range: 5.9 to 6.5 V (typ. 6.2 V)
- Low temperature coefficient range: max. 0.0005 to 0.01 %/K.

APPLICATION

• Voltage reference sources in measuring instruments such as digital voltmeters.

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
IZ	working current		_	50	mA
P _{tot}	total power dissipation	T _{amb} = 50 °C	_	400	mW
T _{stg}	storage temperature		-65	+200	°C
Tj	junction temperature		_	200	°C
T _{amb}	operating ambient temperature		0	+70	°C

DESCRIPTION

Voltage reference diode in a hermetically-sealed SOD68 (DO-34) glass package.

Fig.1 Simplified outline (SOD68; DO-34) and symbol.

BZV10 to BZV14

ELECTRICAL CHARACTERISTICS

 $T_{amb} = 25 \circ C$ unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V _{ref}	reference voltage	I _Z =2 mA	5.9	6.2	6.5	V
ΔV _{ref}	reference voltage excursion	I _Z =2 mA; test points for				
	BZV10	T _{amb} : 0; +25; +70 °C; notes 1 and 2	_	_	46	mV
	BZV11		_	_	23	mV
	BZV12		_	_	9	mV
	BZV13		_	_	4.6	mV
	BZV14		_	_	2.3	mV
S _Z	temperature coefficient	I _Z = 2 mA: see Fig.2;				
	BZV10	notes 1 and 2	_	_	0.01	%/K
	BZV11		-	-	0.005	%/K
BZV12 BZV13 BZV14		_	_	0.002	%/K	
	BZV13		_	_	0.001	%/K
	BZV14		-	_	0.0005	%/K
r _{dif}	differential resistance	I _Z = 2 mA; see Fig.3	_	20	50	Ω

Notes

- 1. The quoted values of ΔV_{ref} are based on a constant current I_Z . Two factors can cause ΔV_{ref} to change, namely the differential resistance r_{dif} and the temperature coefficient S_Z .
 - a) As the max. r_{dif} of the device can be 50 Ω , a change of 0.01 mA in the current through the reference diode will result in a ΔV_{ref} of 0.01 mA \times 50 Ω = 0.5 mV. This level of ΔV_{ref} is not significant on a BZV10 (ΔV_{ref} < 46 mV), it is however very significant on a BZV14 (ΔV_{ref} < 2.3 mV).
 - b) The temperature coefficient of the reference voltage S_Z is a function of I_Z. Reference diodes are classified at the specified test current, and the S_Z of the reference diode will be different at different levels of I_Z. The absolute value of I_Z is important, however, the stability of I_Z, once the level has been set, is far more significant. This applies particularly to the BZV13 and BZV14. The effect of the stability of I_Z on S_Z is shown in Fig.2.
- 2. All reference diodes are characterized by the 'box method'. This guarantees a maximum voltage excursion (ΔV_{ref}) over the specified temperature range, at the specified test current (I_Z), verified by tests at indicated temperature points within the range. V_Z is measured and recorded at each temperature specified. The ΔV_{ref} between the highest and lowest values must not exceed the maximum ΔV_{ref} given. Therefore the temperature coefficient is only given as

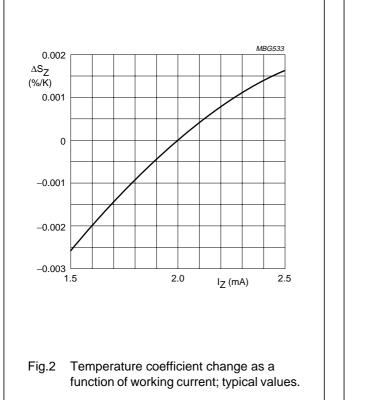
a reference. It may be derived from:
$$S_{Z} = \frac{V_{ref1} - V_{ref2}}{T_{amb2} - T_{amb1}} \times \frac{100}{V_{ref nom}} %/K$$

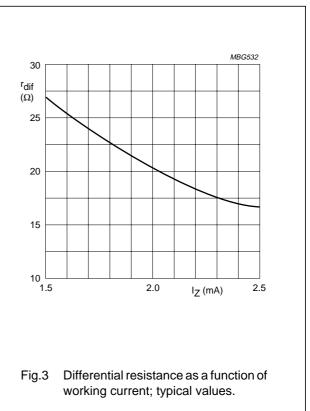
THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	CONDITIONS	VALUE	UNIT
R _{th j-tp}	thermal resistance from junction to tie-point	8 mm from the body	300	K/W
R _{th j-a}	thermal resistance from junction to ambient	lead length 10 mm	375	K/W

BZV10 to BZV14

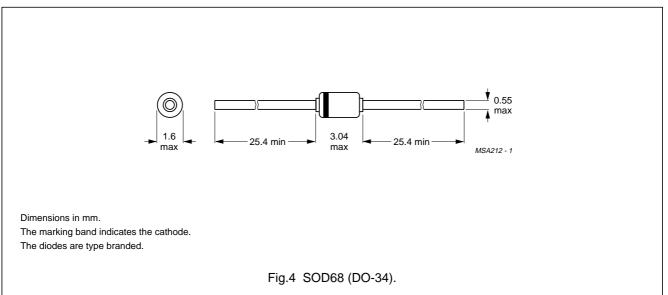
GRAPHICAL DATA





BZV10 to BZV14

PACKAGE OUTLINE



DEFINITIONS

Data Sheet Status			
Objective specification	This data sheet contains target or goal specifications for product development.		
Preliminary specification	This data sheet contains preliminary data; supplementary data may be published later.		
Product specification	This data sheet contains final product specifications.		
Limiting values			
Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.			
Application information			
Where application information is given, it is advisory and does not form part of the specification.			

LIFE SUPPORT APPLICATIONS

These products are not designed for use in life support appliances, devices, or systems where malfunction of these products can reasonably be expected to result in personal injury. Philips customers using or selling these products for use in such applications do so at their own risk and agree to fully indemnify Philips for any damages resulting from such improper use or sale.